


<b>Search Notes</b>  	<b>Application/Control No.</b>  10591920	<b>Applicant(s)/Patent Under Reexamination</b>  TOBE ET AL.
	<b>Examiner</b>  DAVID WEISZ	<b>Art Unit</b>  1797

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
UpdatedEAST text search (see search history) , Updated Inventor search in PALM, Updated google text search (arylene, crown ether, chiral sensor)	5/21/2010	/DW/
Consultation with Vickie Kim, SPE 1797	1/29/2010	/DW/
STN search (see search history)	12/16/2008	/DW/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
436	106, 107, 164-172	5/21/2010	/DW/
549	347	5/21/2010	/DW/

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